

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 08-015318

(43)Date of publication of application : 19.01.1996

(51)Int.Cl.

G01R 1/073
G01R 31/28
H01L 21/66

(21)Application number : 06-164701

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(22)Date of filing : 23.06.1994

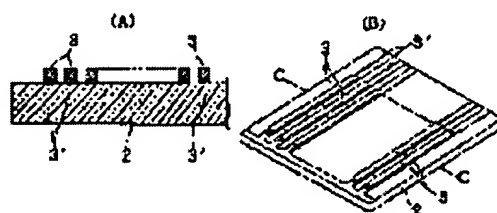
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(54) PROBE UNIT AND MANUFACTURE THEREOF

(57)Abstract:

PURPOSE: To obtain a probe unit provided with resilient contact pieces by projecting the end part of a lead group arranged at a fine pitch on the surface of a base board from the base board in which the lead group can be formed soundly and easily without requiring the work for bonding the lead group to the base board.

CONSTITUTION: A large number of leads 3 are grown by plating on the surface of a base board 2 and a resilient contact piece 3a is formed at one end of the lead 3 projected from one end of the base board 2. First and second base boards are then abutted each other on the end faces thereof and a large number of leads are grown by plating on the surface of the first and second base boards while traversing both base boards and being arranged side by side. Finally, the second base board is stripped and the lead terminals extending on the second base board are projected from the end part of the first base board.



LEGAL STATUS

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[Date of request for examination] 23.06.1994

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number] 2599895

[Date of registration] 09.01.1997

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right] 09.01.2004

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